Docket No.

240306US2

#### IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF:

Fumihiko SANO

SERIAL NO: New Application

GAU:

FILED:

Herewith

**EXAMINER:** 

FOR:

SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE AND METHOD OF MANUFACTURING THE SAME

## INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

Applicant(s) wish to disclose the following information.

#### REFERENCES

- The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- A check is attached in the amount required under 37 CFR §1.17(p).

#### RELATED CASES

- Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- A check is attached in the amount required under 37 CFR §1.17(p).

#### CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

#### DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND, MAIER & NEUSTADT, P.C.

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## **STATEMENT OF RELEVANCY**

# Reference AO (8-274258) on Form PTO-1449:

Making some conductive trenches under the electrical-PAD, and behaving as "bypass-condenser" between Power and Ground.

# Reference AP (2001-102529) on Form PTO-1449:

Capacitor Device constructed with MIM (Metal-Insulator-Metal) in the Semiconductor integrated circuit.

Form PTO 1449 U.S. DEPARTMENT OF COMMERCE (Modified) PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO. 240306US2		SERIAL NO. New Application			
LIST OF	REFE	RENCES CITED BY AP	PLIĊANT	APPLICANT Fumihiko SANO				
·				FILING DATE		GROUP		
				Herewith				
U.S. PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
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FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY		TRANSLATION YES NO		
	AO	8-274258	10/18/96	Japan (with English Abstract)			X	
	AP	2001-102529	04/13/01	Japan (with English Abstract)			X	
	AQ							
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)								
	AW							
	AX							
	AY							
	AZ				Addi	Additional References sheet(s) attached		
Examiner					Date Cor	Date Considered		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								
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